

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS21S07A	Feb-97	9648 B2	ANAM, PI.	DK636057AAB1	0.8μ NITRIDE	20 TSSOP

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
HTC Vapor Phase
P-19071

<u>Electrical</u>	<u>Cum %</u>
235/0	0.0%

Sonoscan
P-19109

<u>Post Vapor Phase</u>
4/0

Infant / High Voltage Life
125°C, 7.0 V.
P-19110, P-19193

<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
230/0	77/0	77/1	67 Fits
		F1	

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 eV; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-19194

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
38/0	38/0	0.0%

Biased Moisture
85°C/85% RH, 5.5 V.
P-19195

<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
77/0	77/0	0.0%

Autoclave
121°C/100% RH, 2 Atmos
P-19196

<u>96 Hr</u>	<u>Cum %</u>
36/0	0.0%

Failure Mode

F1: Functional

Failure Analysis

In process